

N-Ch MOSFET

General Description

The WST4040 is the highest performance trench N-ch MOSFETs with extreme high cell density , which provide excellent R_{DSON} and gate charge for most of the synchronous buck converter applications .

The WST4040 meet the RoHS and Green Product requirement,100% EAS guaranteed with full function reliability approved.

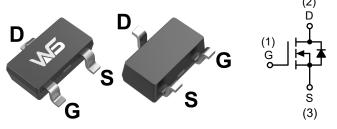
Product Summery

BV _{DSS}	R _{DSON}	Ι _D
40V	35mΩ	5.8A

Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

SOT-23-3L Pin Configuration



Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	40	V
V _{GS}	Gate-Source Voltage	±20	V
I _D @T _C =25℃	Continuous Drain Current, V _{GS} @ 4.5V ¹	5.8	A
I _D @T _C =70℃	Continuous Drain Current, V _{GS} @ 4.5V ¹	2.5	А
I _{DM}	Pulsed Drain Current ²	16	A
P _D @T _A =25℃	Total Power Dissipation ³	1.0	W
T _{STG}	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter		Max.	Unit
R _{eJA}	Thermal Resistance Junction-ambient ¹		125	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹		75	℃/W



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Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	40			V
$\triangle BV_{DSS} / \triangle T_{J}$	BV _{DSS} Temperature Coefficient	Reference to 25 $^\circ\!\mathrm{C}$, I_D=1mA		0.03		V/℃
Б	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =3A		35	50	
R _{DS(ON)}		V _{GS} =4.5V , I _D =2A		50	60	mΩ
V _{GS(th)}	Gate Threshold Voltage		0.6	1.0	1.6	V
	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, $I_D=250$ uA		4.5		mV/℃
		$V_{\text{DS}}\text{=}32\text{V}$, $V_{\text{GS}}\text{=}0\text{V}$, $T_{\text{J}}\text{=}25^\circ\!\!\mathrm{C}$			1	
I _{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}\text{=}32\text{V}$, $V_{\text{GS}}\text{=}0\text{V}$, $T_{\text{J}}\text{=}55^\circ\!\mathrm{C}$			5	uA
I _{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm20V$, $V_{DS}=0V$			±100	nA
gfs	orward Transconductance V _{DS} =5V , I _D =3A			18		S
R _g	Gate Resistance	te Resistance V _{DS} =0V , V _{GS} =0V , f=1MHz		1.7		Ω
Qg	Total Gate Charge (4.5V)			6.5	12.5	
Q _{gs}	Gate-Source Charge	V_{DS} =20V , V_{GS} =4.5V , I_{D} =2A		0.8	3.5	nC
Q _{gd}	Gate-Drain Charge			1.65	4.2	
T _{d(on)}	Turn-On Delay Time			1.5	4.8	
Tr	Rise Time	V_{DD} =20V , V_{GS} =10V , R_{G} =3.3 Ω		42	14	
T _{d(off)}	Turn-Off Delay Time	I _D =1A		18	44	ns
T _f	Fall Time			5.9	8	
C _{iss}	Input Capacitance			396	497	
Coss	Output Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		47	112	pF
C _{rss}	Reverse Transfer Capacitance			35	91	

Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy⁵	V _{DD} =25V , L=0.1mH , I _{AS} =2A	9			mJ

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current ^{1,6}				1	А
I _{SM}	Pulsed Source Current ^{2,6}	$V_G = V_D = 0V$, Force Current			16	А
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , TJ=25℃			1.2	V
t _{rr}	Reverse Recovery Time	<code>IF=2A</code> , <code>dl/dt=100A/µs</code> , <code>T_J=25</code> $^\circ\!\!\!\!\!\!\mathrm{C}$		18		nS
Qrr	Reverse Recovery Charge	IF=2A , dI/dt=100A/µs , T _J =25℃		70		nC

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper,t<10sec.

2.The data tested by pulsed , pulse width $\,\leq\,$ 300us , duty cycle $\,\leq\,$ 2%

3.The EAS data shows Max. rating . The test condition is V_{DD} =25V, V_{GS} =10V,L=0.1mH,I_{AS}=2A

4. The power dissipation is limited by 150 °C junction temperature

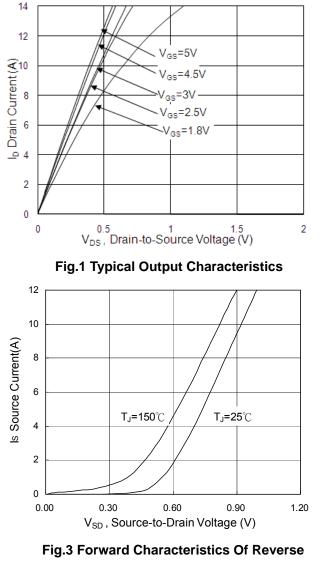
5. The Min. value is 100% EAS tested guarantee.

6.The data is theoretically the same as I_{D} and I_{DM} , in real applications , should be limited by total power dissipation.



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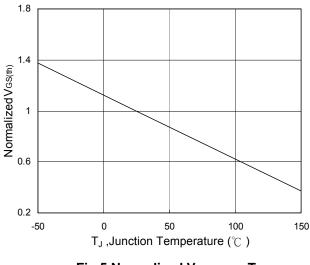


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

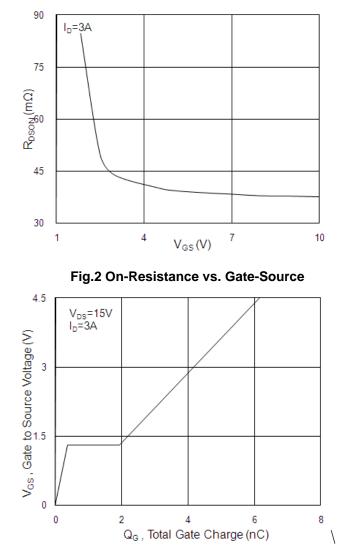


Fig.4 Gate-Charge Characteristics

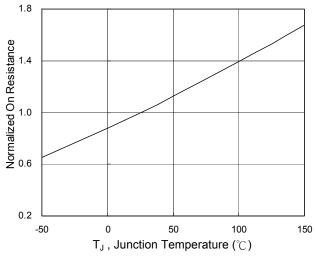


Fig.6 Normalized R_{DSON} vs. T_J



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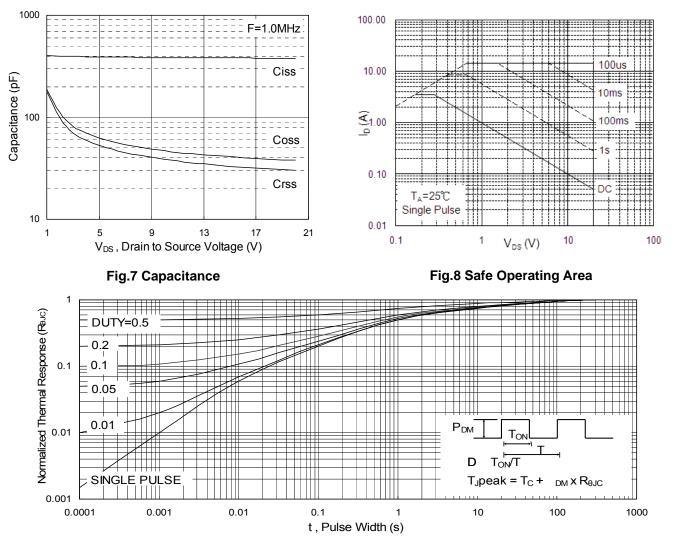
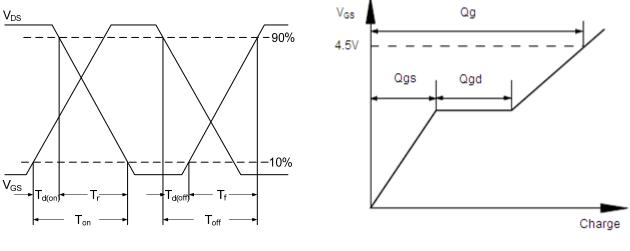


Fig.9 Normalized Maximum Transient Thermal Impedance



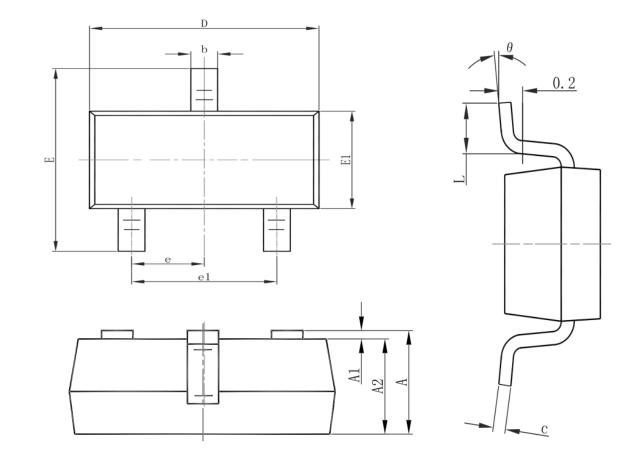






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Packaging information



Complete L	Dimensions In Millimeters		Dimensio	ns In Inches
Symbol	Min.	Max.	Min.	Max.
А	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
с	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
E	2.650	2.950	0.104	0.116
е	0.950	0.950(BSC)		7(BSC)
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°



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